Einladung zum Vortrag

25. Oktober 2016, 14.00 Uhr s.t.
(ACHTUNG | SONDERTERMIN AUSSER DER REIHE)
Universität Bremen | MZH 4380

Dr. Daniel Tille
Infineon Technologies AG

Testing IoT-Designs: How to make the impossible possible?

The Internet-of-Things (IoT) era has started. Billions of sensors and actuator devices will connect the world. It creates a new market for very small and cost-sensitive chips. Such designs must fulfill requirements as for example low power consumption and small form factor. Furthermore, design costs must be as low as possible in order to be competitive. At the same time, each device must be tested in order to check for its correct functionality. Unfortunately, the IoT requirements contradict a good testability.

This presentation shows the general problems of poor testability of IoT designs from an industrial point of view and motivates why effective Design-for-Test (DFT) methods are required. It will present new approaches of how to improve testability of IoT designs while keeping the designs costs low.

Biografie

Daniel Tille has been with Infineon Technologies AG since 2012. He is responsible for the DFT Concept in the development of Automotive- and Chip Card microcontrollers. Before, he worked at Verified Systems and Daimler AG on new methods for Automatic Test Generation in the Automotive Domain. He received his Diploma in Computer Science from Martin-Luther-University Halle-Wittenberg in 2006 and his PhD from University of Bremen in 2011.

Dieser Gast wurde von Rolf Drechsler eingeladen.